

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10580352	TAKASHI ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Stefan Kruer	3654

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
187	351,356,367,378,379, 371, 372, 374	03/30/2008	SHK
104	252, 257		
187	414	06/19/2008	SHK
B66B	5/00, 5/04, 7/00, 7/02		
104	127 - 128		

<b>SEARCH NOTES</b>			
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>	
PLUS	03/30/2008	SHK	
248 + word			

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
US PGPUBS		06/19/2008	SHK